Search Notes					

Application/Control No.	Applicant(s)/Paten Reexamination	t under
10/826,207	LEE ET AL.	
Examiner	Art Unit	:
Matthew D. Matzek	1771	

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Class	Subclass	Date	Examiner
442	13-0	10/7/07	мм
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
ASSIGNEE	10/7/07	µ s	
EHT	10/7/05 / 3/23/06 A	иД	
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